

<b>Notice of References Cited</b>	Application/Control No. 10/046,926	Applicant(s)/Patent Under Reexamination TEIG ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,070,108	05-2000	Andreev et al.	700/121
	B	US-6,415,422 B1	07-2002	Mehrotra et al.	716/5
	C	US-6,557,145 B2	04-2003	Boyle et al.	716/2
	D	US-6,480,991 B1	11-2002	Cho et al.	716/8
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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